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U.S. PATENT DOCUMENTS

*EXAMINER		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
	E.							
	F.							
	G.							
	H.							

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

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H Pham	3/3/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.